## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No	10/624,340
Confirmation No	
	July 21, 2003
Inventor	Brent A. McClure
Assignee	Micron Technology, Inc.
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	Ml22-2067
Customer No	021567
Title: Capacitor Constructions and Ma	

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## INFORMATION DISCLOSURE STATEMENT

## References - See Attached Form PTO-1449

The Examiner's attention is directed to the references which are listed on the attached Form PTO-1449. Pursuant to 37 C.F.R. §1.98(a)(2)(1) no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether all the submitted references are prior art.

Citation of the referenced art is respectfully requested.

Respectfully submitted,

Dated: 09 Mar 2005

By:

James E. Lake V Reg. No. 44,854

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